High-Frequency Probe

HFS-840 201 051 A 8006

Item HFS-840-0285

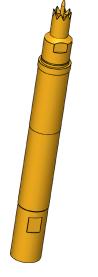






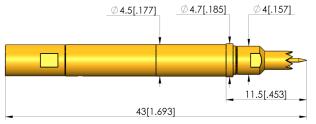
- Up to 4 GHz
- Cable interface MCX
- Plug-in version
- Receptacles: KS-810, KS-810 R, KS-810 F

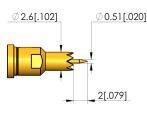












General data

Product group: HFS radio-frequency test probes HFS-840 Series: Sub-series: HFS-840 Grid: 5.8 mm [228 mil] DUT / contact: PCB coax, closed Installation type: Plug-in Floating mount: No Non-rotating: Yes Continuous plunger: Yes Interface of compatible assembly: MCX 50 Ohm Compatible assembly interface gender: M signal conductor male / pin KS sub-series: KS-810, press-in version Min. temperature: -40 °C [-40 °F] Max. temperature: 80 °C [176 °F]

Outer conductor data

RoHS-compliant:

Outer conductor tip style: 06 serrated Outer conductor tip style diameter: 2.6 mm [.102 in] Spring force of entire outer conductor at working stroke: 6 N [21.5 ozf] Outer conductor working stroke: 4 mm [.157 in] Outer conductor maximum stroke: 5 mm [.196 in] KO-810-0156 Exchangeable outer conductor: Outer conductor max. current load capacity: 10 A

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Inner conductor data

Inner conductor tip style: 01 30° needle tip, self-cleaning Inner conductor tip style diameter: 0.51 mm [.02 in] Inner conductor tip style material: 2 steel Inner conductor tip style surface: A gold Number of inner conductors: Exchangeable inner conductor: GKS-051-0007 Inner conductor working stroke: 2 mm [.078 in] Spring force of each inner conductor at working stroke: 2 N [7.19 ozf] Inner conductor maximum stroke: 3.7 mm [.145 in] Inner conductor max. current load capacity: 2 A

Electrical data

Yes

4 GHz Frequency range up to: 50 Ohm Impedance:

Mechanical data

Total spring force at working stroke: 8 N [28.7 ozf] Total length: 43 mm [1.69 in] 4.5 mm [.177 in] Barrel diameter: Installation height without receptacle: 11.5 mm [.452 in]

> Learn more about Radio-frequency test probes



